## Amendments to the Claims

The listing of claims will replace all prior versions, and listings, of claims in the application.

### Listing of Claims:

1. (Previously Presented) A method for verifying an integrated circuit device test for testing an integrated circuit device, said method comprising the steps of:

simulating a flawed integrated circuit device design comprising a good integrated circuit design modified to include one or more known physical flaws in the good integrated circuit device design;

simulating said integrated circuit device test to test said simulated flawed integrated circuit device design; and

determining whether said simulated test of said simulated flawed integrated circuit device design discovered said one or more known physical flaws in said simulated flawed integrated circuit device design.

2. (Canceled)

3. (Currently Amended) The method of claim [[3]] 1, further comprising the step of:

indicating that said integrated circuit device test is flawed if said simulated test of said simulated flawed integrated circuit device design does not discover said one or more known physical flaws in said simulated flawed integrated circuit device design.

4. (Previously Presented) The method of claim 1, further comprising the step of:

indicating that said integrated circuit device test is flawed if said simulated test of said simulated flawed integrated circuit device design does not discover